

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Rankin, *et al.*

Examiner: Doty, Heather Anne

Serial No.: 10/710,602

Group Art Unit: 2813

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Docket No.: **BUR920040086US1**

Title: **METHOD TO SELECTIVELY CORRECT CRITICAL DIMENSION ERRORS IN
THE SEMICONDUCTOR INDUSTRY**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

OFFICE ACTION RESPONSE

Sir:

This communication is in response to the Final Office Action mailed August 21, 2006.